

IRL2203NL-VB Datasheet

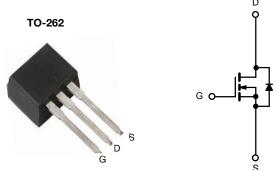
N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}$ (Ω)	I _D (A)	Q _g (Typ)			
30	0.0023 at V _{GS} = 10 V	150	82 nC			
	0.0032 at $V_{GS} = 4.5 \text{ V}$	120	02 110			

FEATURES

- Trench Power MOSFET
- 100 % R_g and UIS Tested
 Compliant to RoHS Directive 2011/65/EU





Top View

N-Channel MOSFET

APPLICATIONS

- OR-ing
- Server
- DC/DC

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	30	V		
Gate-Source Voltage	V _{GS}	± 20			
	T _C = 25 °C		150		
Continuous Drain Current (T _{.I} = 175 °C)	T _C = 70 °C	L	120	A	
Continuous Diam Current (1) = 173 C)	T _A = 25 °C	I _D	35.8 ^{b, c}		
	T _A = 70 °C		27 ^{b, c}		
Pulsed Drain Current	I _{DM}	500			
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	39		
Single Pulse Avalanche Energy		E _{AS}	94.8	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	l.	90 ^{a, e}	^	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	3.13 ^{b, c}	A	
	T _C = 25 °C		250 ^a		
Manianum Danian Dinain ation	T _C = 70 °C	P _D	175	10/	
Maximum Power Dissipation	T _A = 25 °C	' D	3.75 ^{b, c}	W	
	T _A = 70 °C		2.63 ^{b, c}		
Operating Junction and Storage Temperature R	T _J , T _{stg}	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Тур.	Max.	Unit		
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 sec	R _{thJA}	32	40	°C/W		
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6	- C/VV		

Notes:

- a. Based on T_C = 25 °C.
 b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 sec. d. Maximum under steady state conditions is 90 °C/W.



SPECIFICATIONS (T _J = 25 °C, unless otherwise noted)							
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	1			1		_	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		35		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$			- 7.5		,	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.5		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	Inco	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ	
Zero Gate Voltage Drain Gurrent	IDSS	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	90			Α	
David Course On Otata Basistana 3	P	$V_{GS} = 10 \text{ V}, I_D = 38.8 \text{ A}$	0.0023				
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 37 \text{ A}$		0.0032		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 38.8 A		160		S	
Dynamic ^b						•	
Input Capacitance	C _{iss}			6201		pF	
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1725			
Reverse Transfer Capacitance	C _{rss}			970			
	0	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 38.8 \text{ A}$		171	257		
		81.5	123				
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 28.8 \text{ A}$		34		nC	
Gate-Drain Charge	Q_{gd}			29			
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t _{d(on)}			18	27		
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 0.625 \Omega$		11	17	ns	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 24$ A, V_{GEN} = 10 V, R_g = 1 Ω		70	105		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			55	83		
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 0.67 \Omega$		180	270		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 22.5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		55	83		
Fall Time	t _f	-		12	18		
Drain-Source Body Diode Characteristic	:S						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			120		
Pulse Diode Forward Current ^a	I _{SM}				120	A	
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			70.2	105	nC	
Reverse Recovery Fall Time	t _a	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		27		ns	
Reverse Recovery Rise Time	t _b			25			

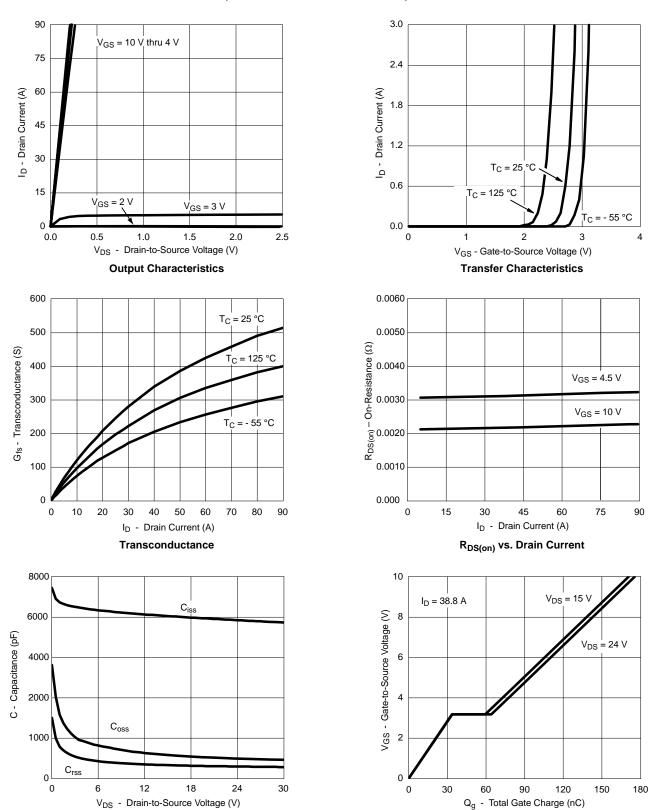
Notes:

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



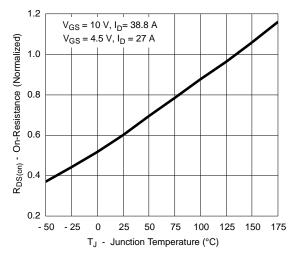
服务热线:400-655-8788

Capacitance

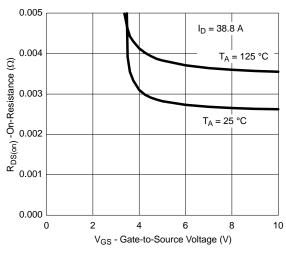
Gate Charge



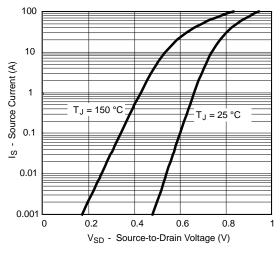
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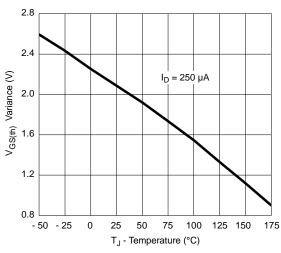
On-Resistance vs. Junction Temperature



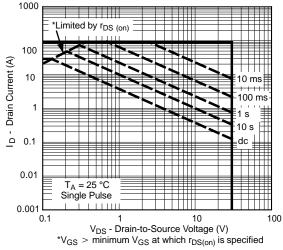
 $R_{DS(on)}$ vs. V_{GS} vs. Temperature



Forward Diode Voltage vs. Temperature



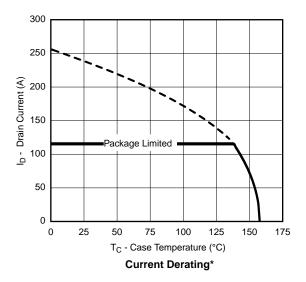
Threshold Voltage

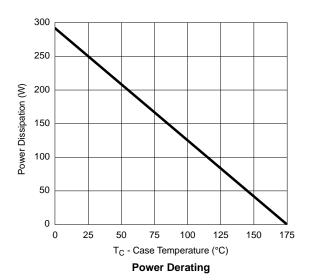


Safe Operating Area, Junction-to-Ambient

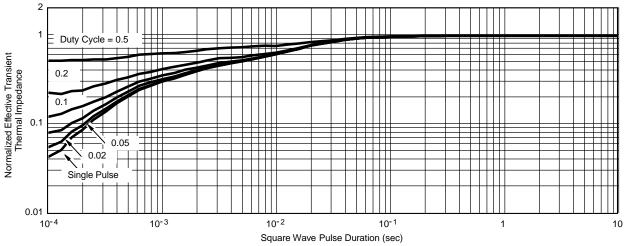


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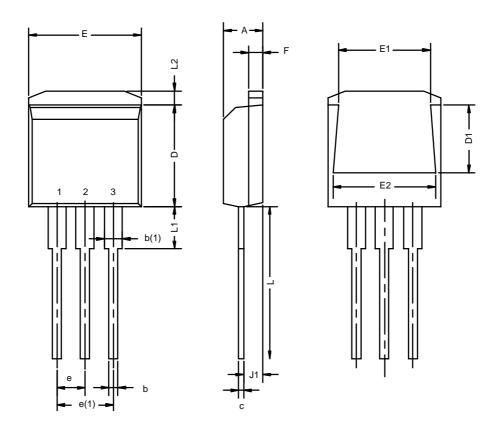
*The power dissipation P_D is based on $T_{J(max)}$ = 175 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case



TO-262: 3-LEAD



	MILLIM	ETERS*	INC	INCHES		
Dim	Min	Max	Min	Max		
Α	4.32	4.70	0.170	0.185		
b	0.64	1.00	0.025	0.039		
b(1)	1.14	1.40	0.045	0.055		
С	0.36	0.50	0.014	0.020		
D	8.64	9.65	0.340	0.380		
D1	5.59	6.10	0.220	0.240		
е	2.41	2.67	0.095	0.105		
e(1)	4.95	5.33	0.195	0.210		
E	10.03	10.41	0.395	0.410		
E1	7.87	8.64	0.310	0.340		
E2	9.02	9.53	0.355	0.375		
F	1.14	1.40	0.045	0.055		
J1	2.41	2.79	0.095	0.110		
L	13.08	14.22	0.515	0.560		
L1	-	3.81	-	0.150		
L2	1.02	1.40	0.040	0.055		
ECN: T-02234—Rev. C, 14-Oct-02 DWG: 5855						

^{*}Use millimeters as the primary measurement



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